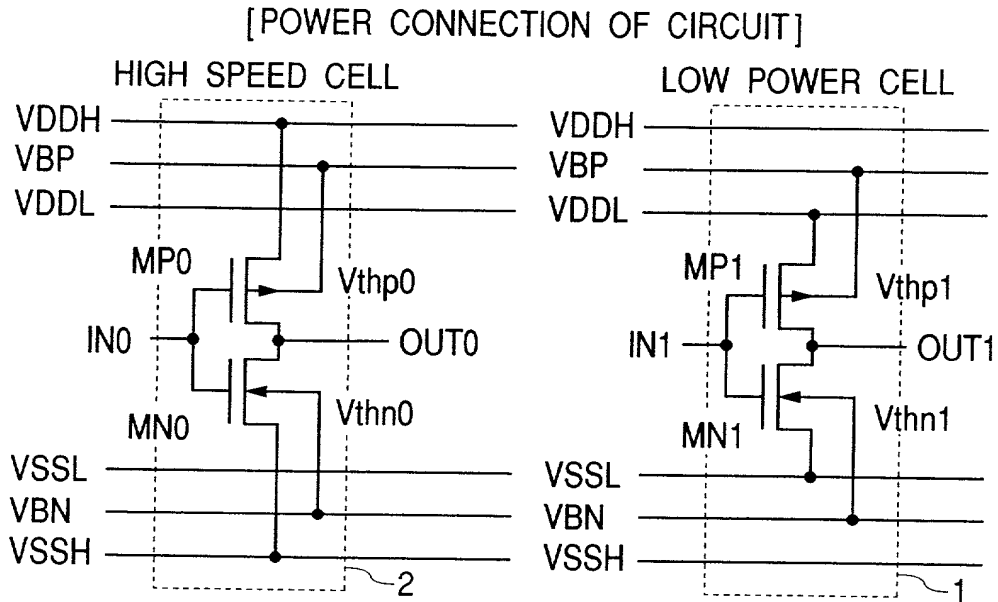
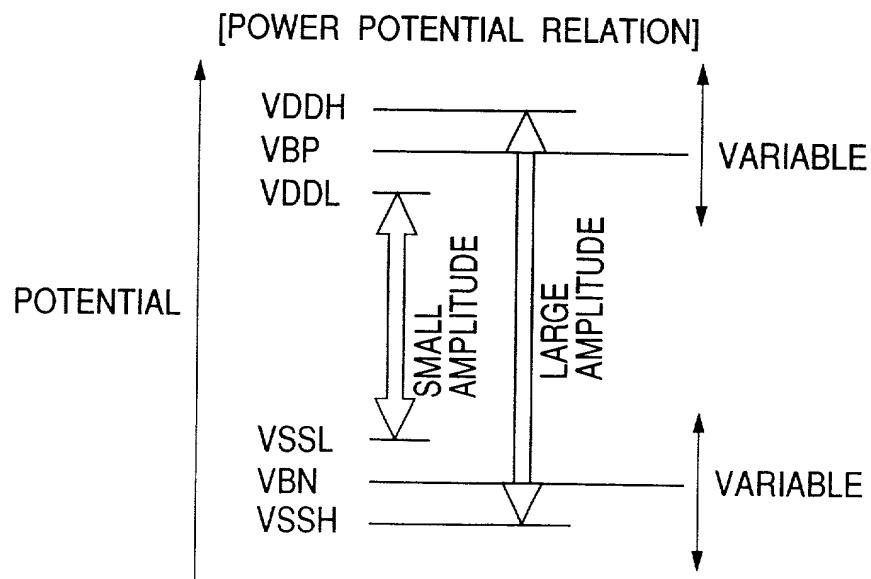
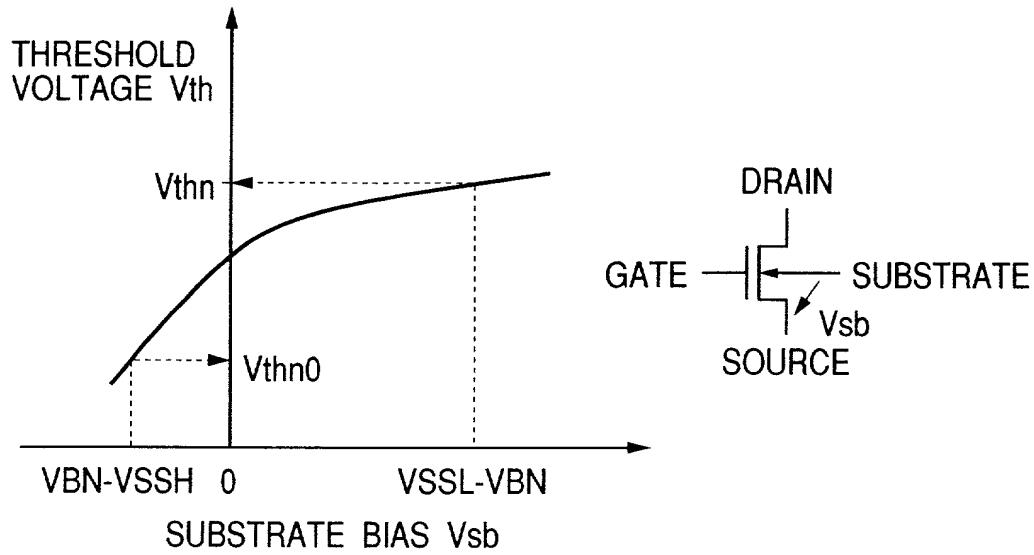


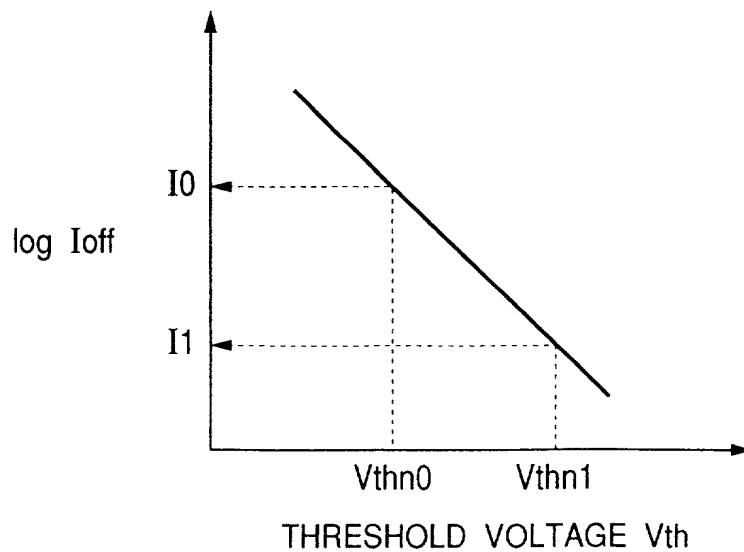
**FIG. 1****FIG. 2**

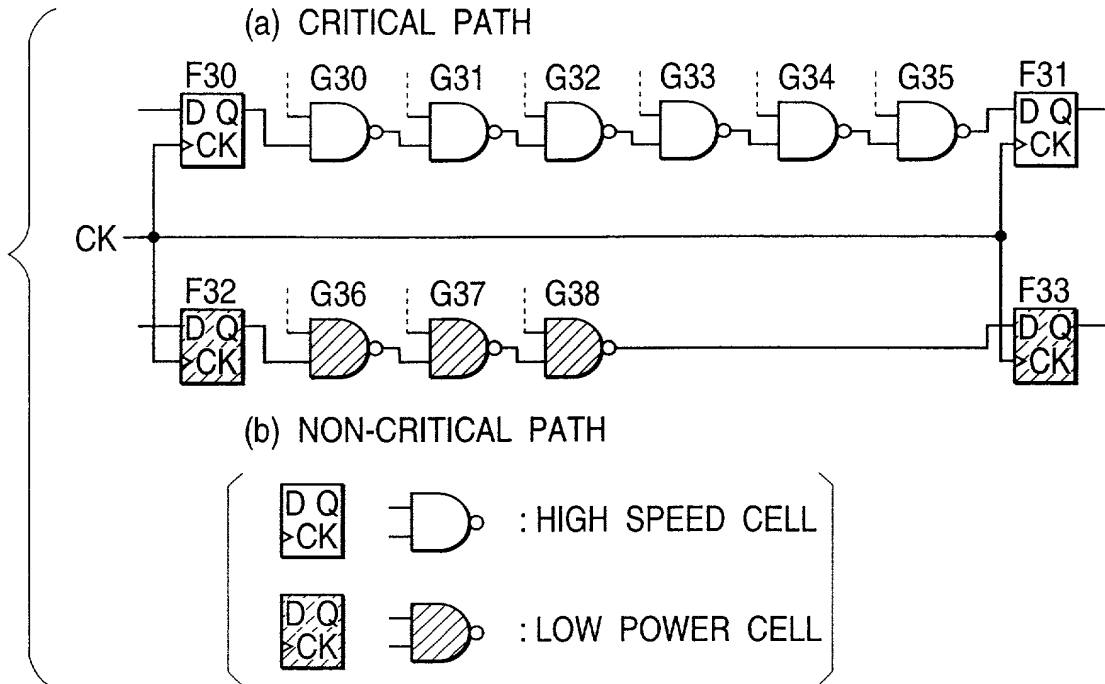
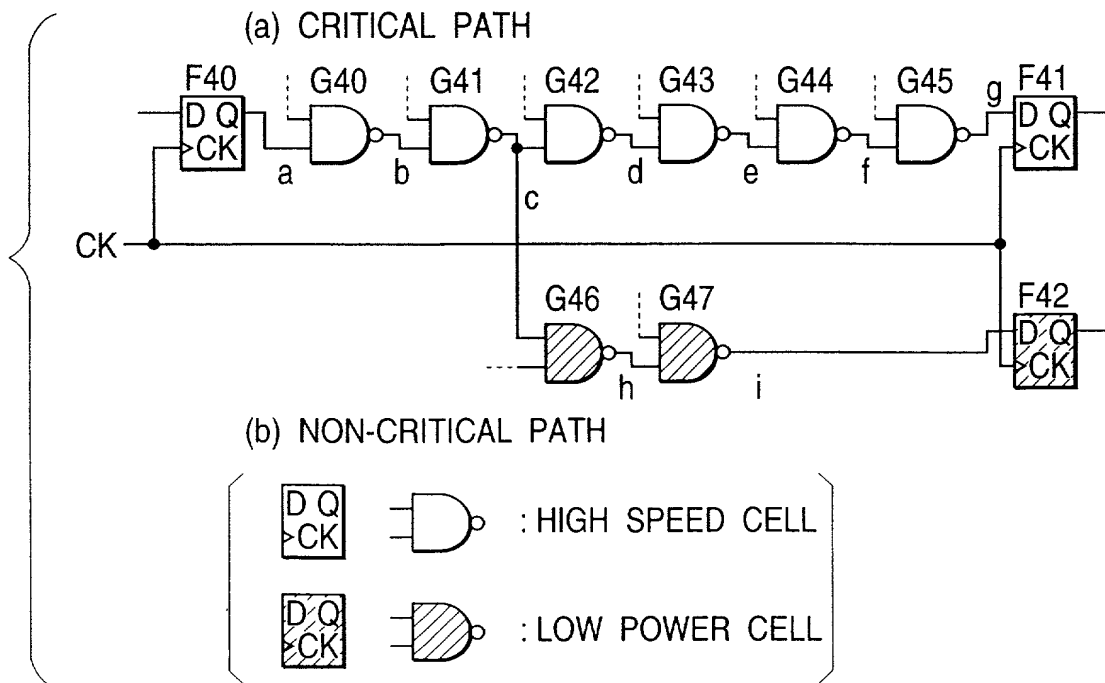
**FIG. 3**

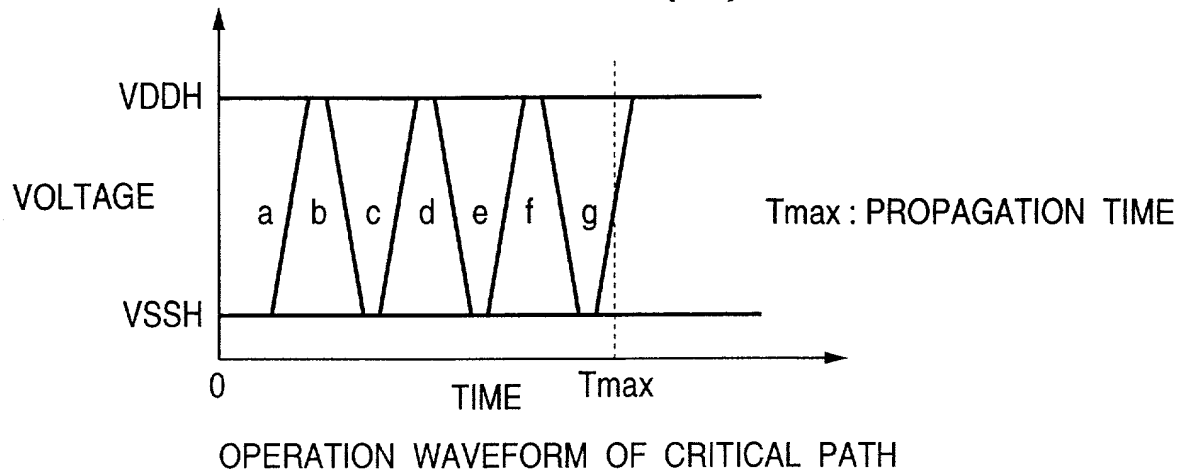
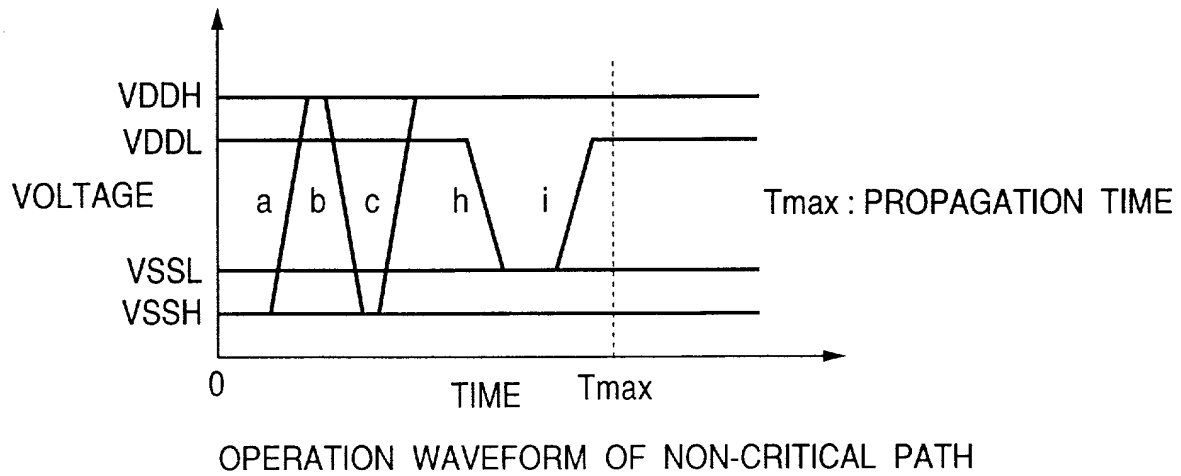
[INCREASE IN THRESHOLD VOLTAGE BY  
APPLICATION OF SUBSTRATE BIAS]

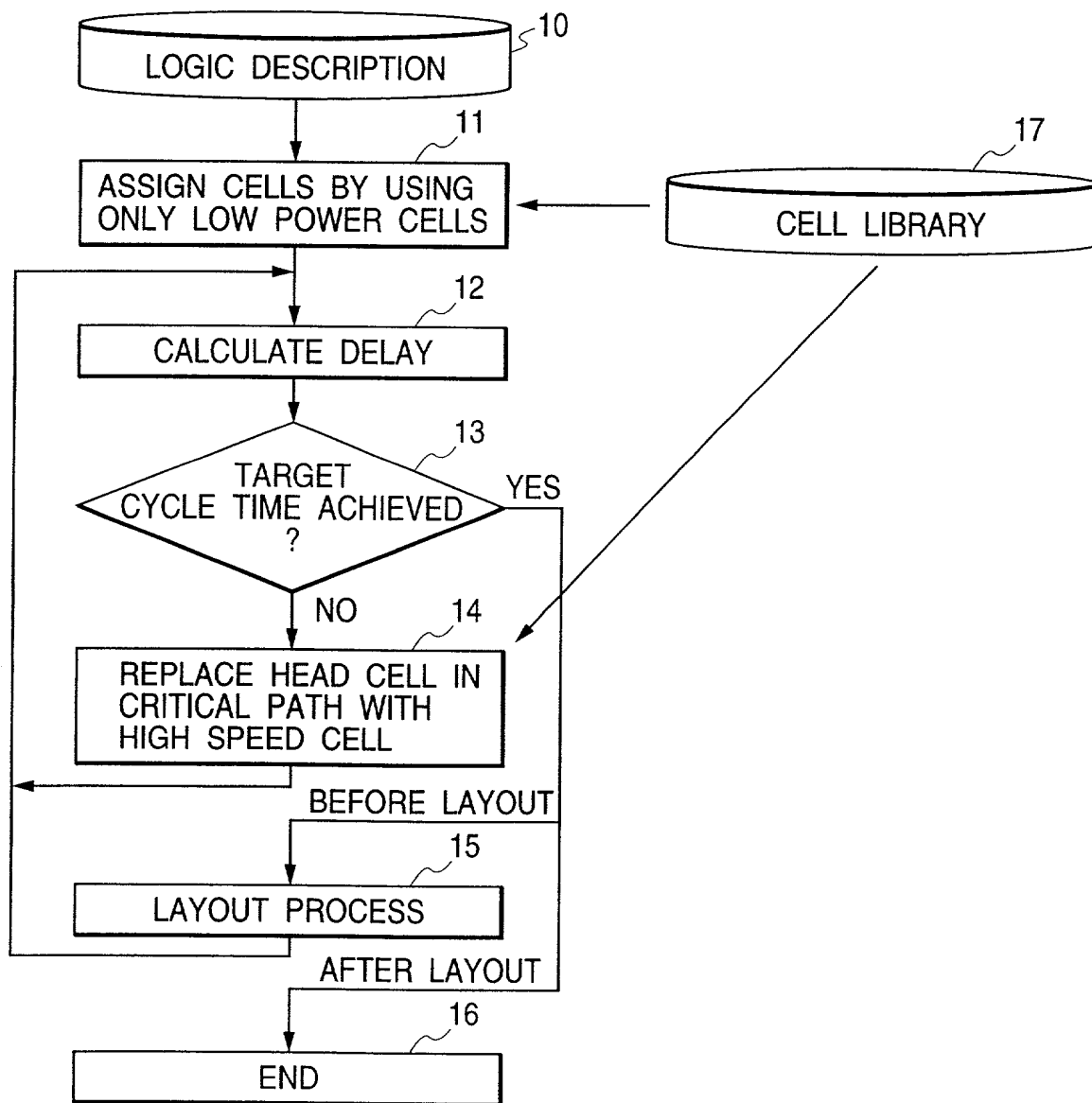
**FIG. 4**

[DECREASE IN LEAK CURRENT BY  
INCREASE IN THRESHOLD VOLTAGE]



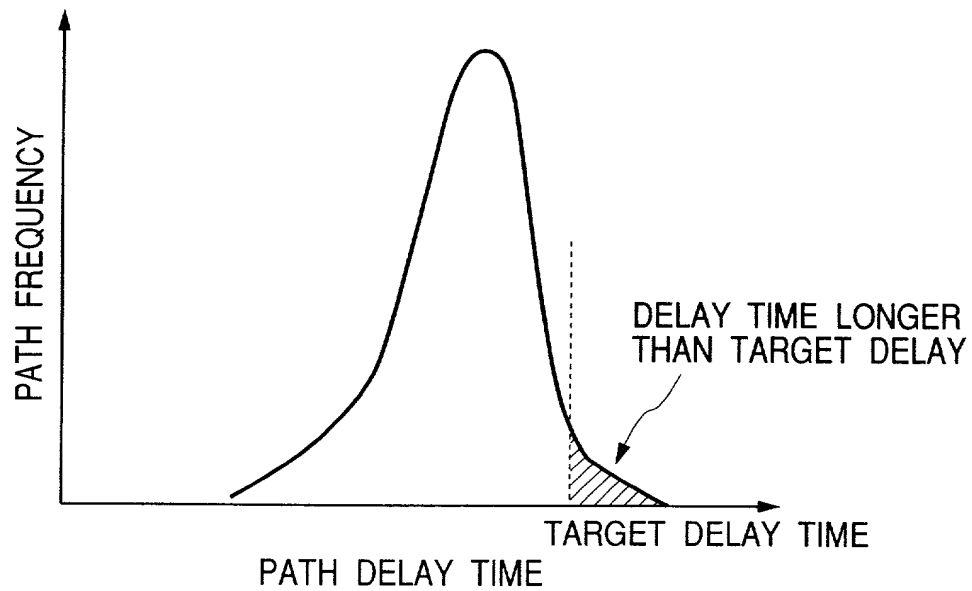
**FIG. 5****FIG. 6**

**FIG. 7(A)****FIG. 7(B)**

**FIG. 8**

**FIG. 9(A)**

[CASE USING ONLY LOW POWER CELLS]



**FIG. 9(B)**

[CASE USING HIGH SPEED CELL FOR CRITICAL PATH]

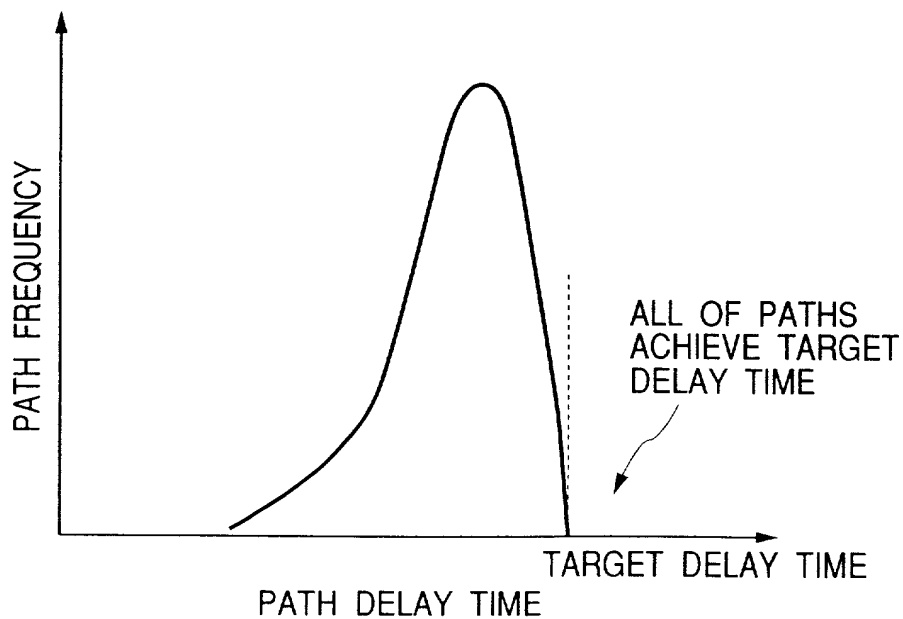


FIG. 10(A)

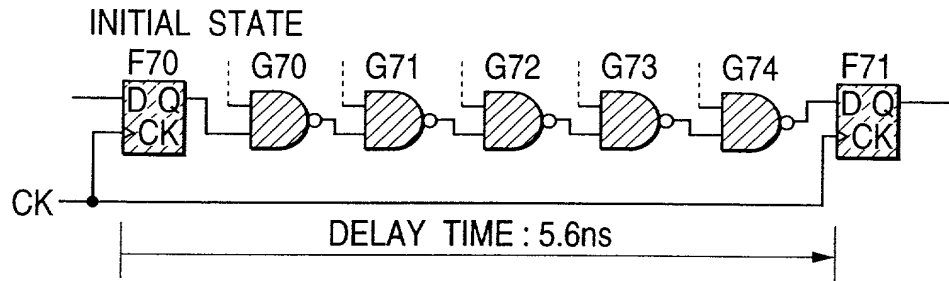


FIG. 10(B)

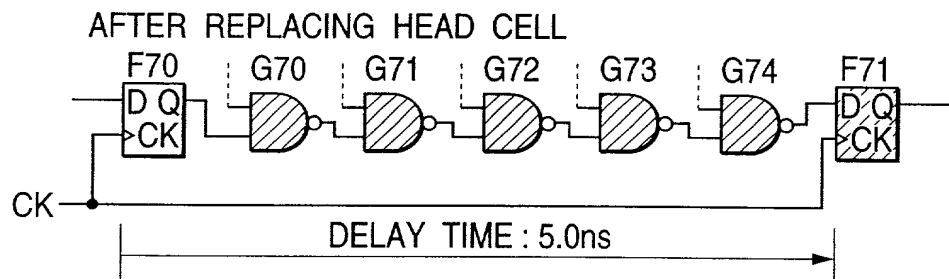


FIG. 10(C)

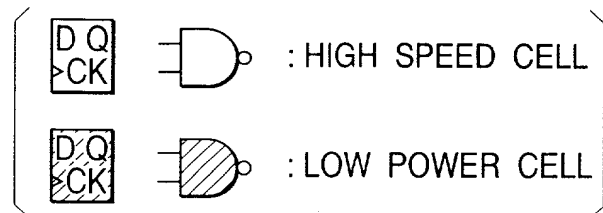
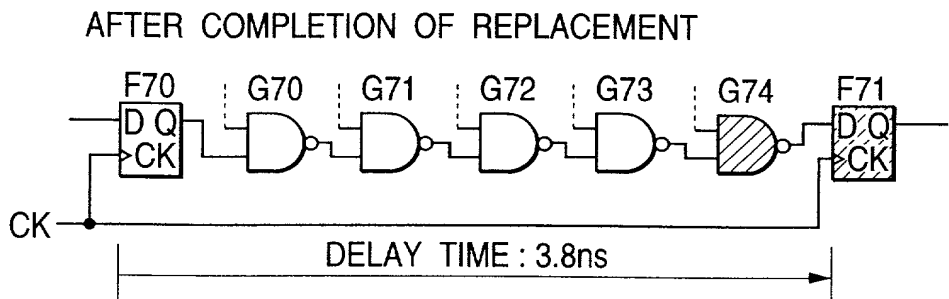
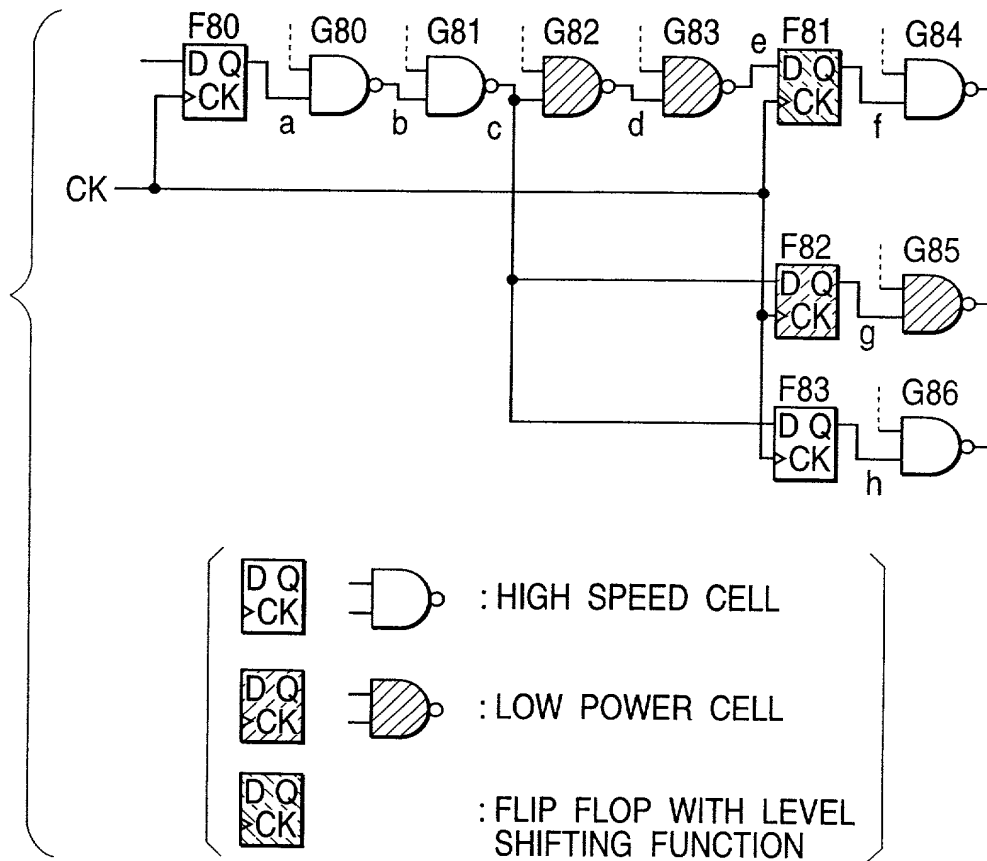


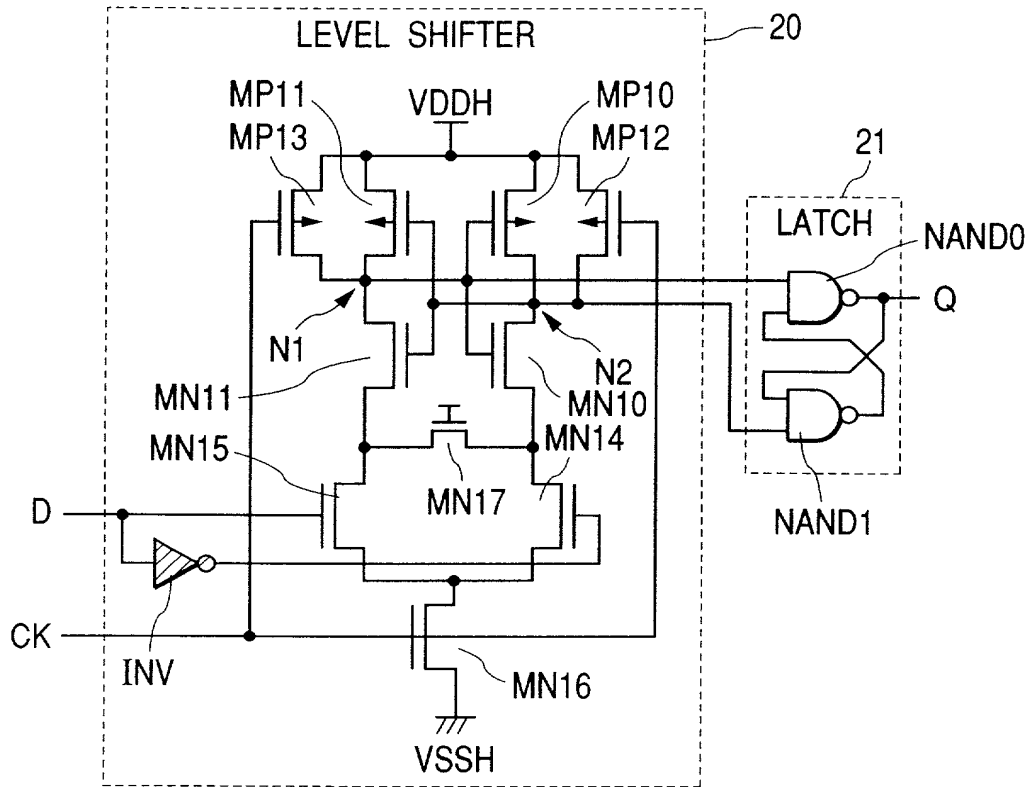
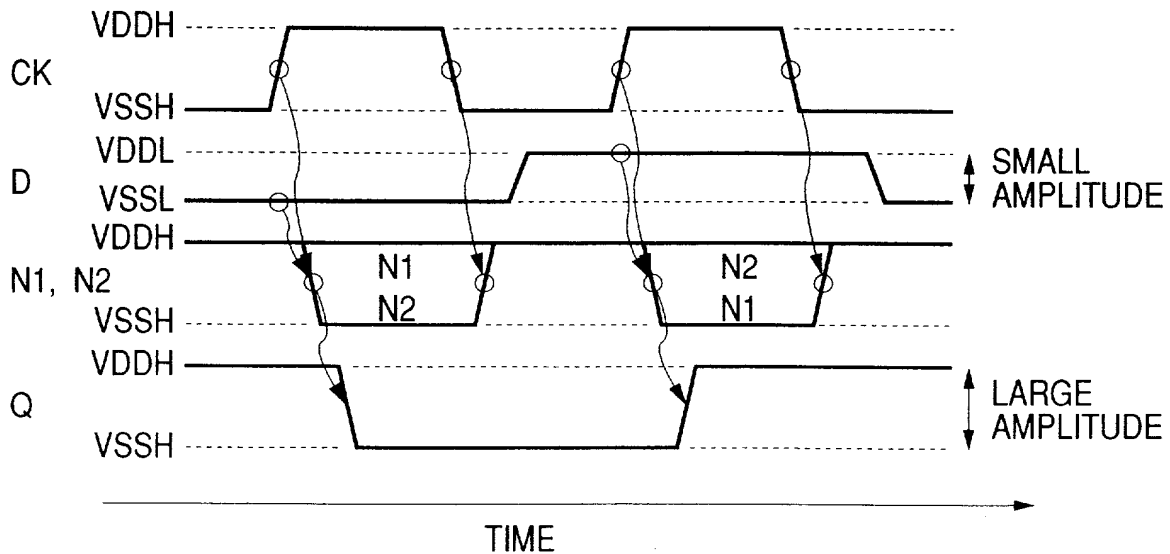
FIG. 11

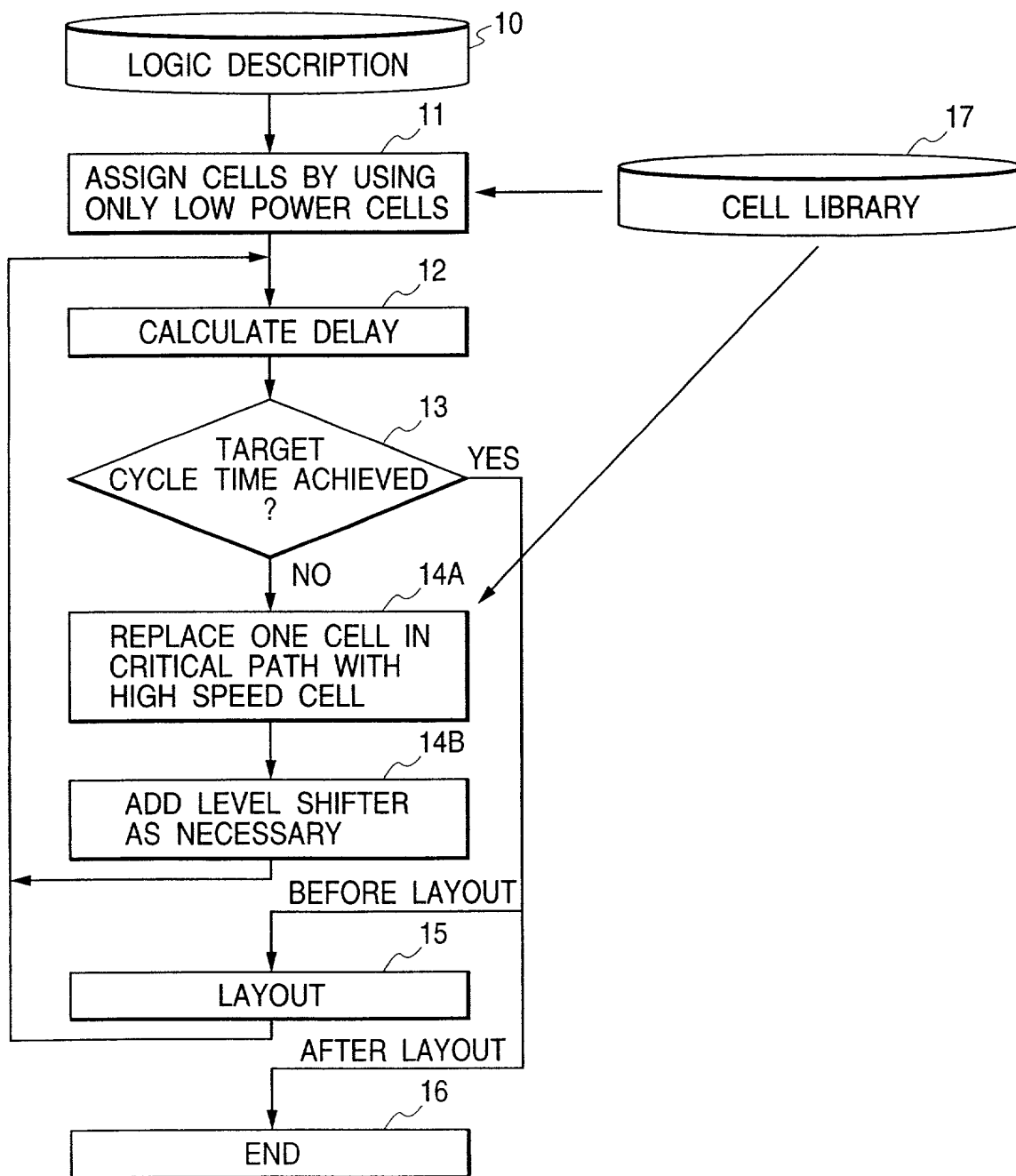




**FIG. 12**

[FLIP FLOP WITH LEVEL SHIFTING FUNCTION]

**FIG. 13**

*FIG. 14*

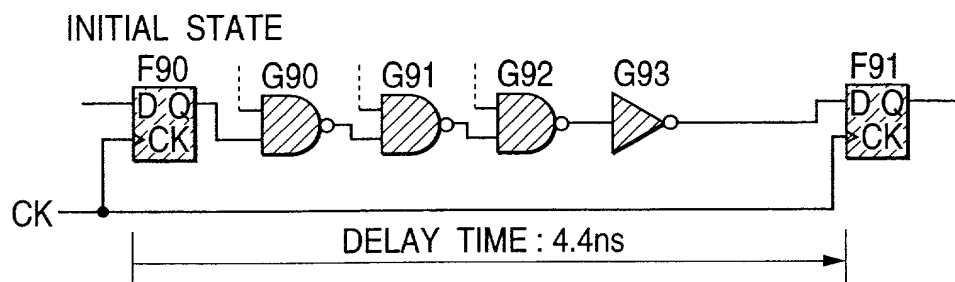
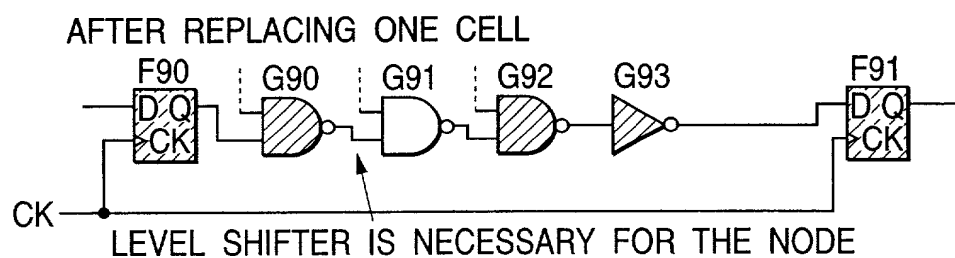
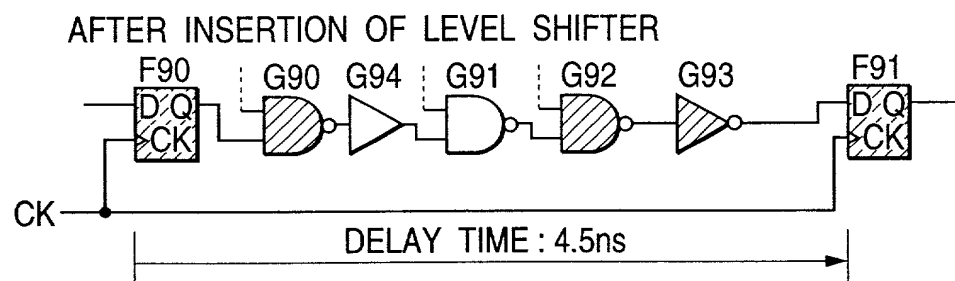
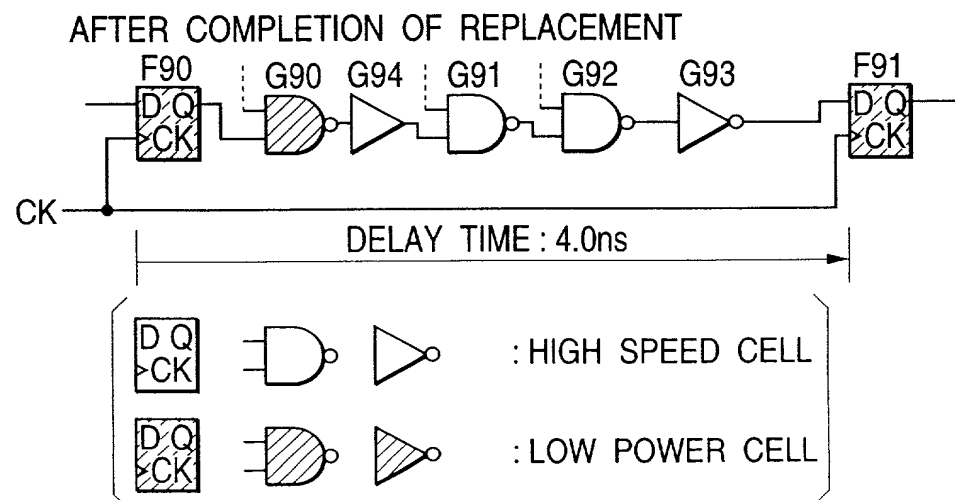
**FIG. 15(A)****FIG. 15(B)****FIG. 15(C)****FIG. 15(D)**

FIG. 16

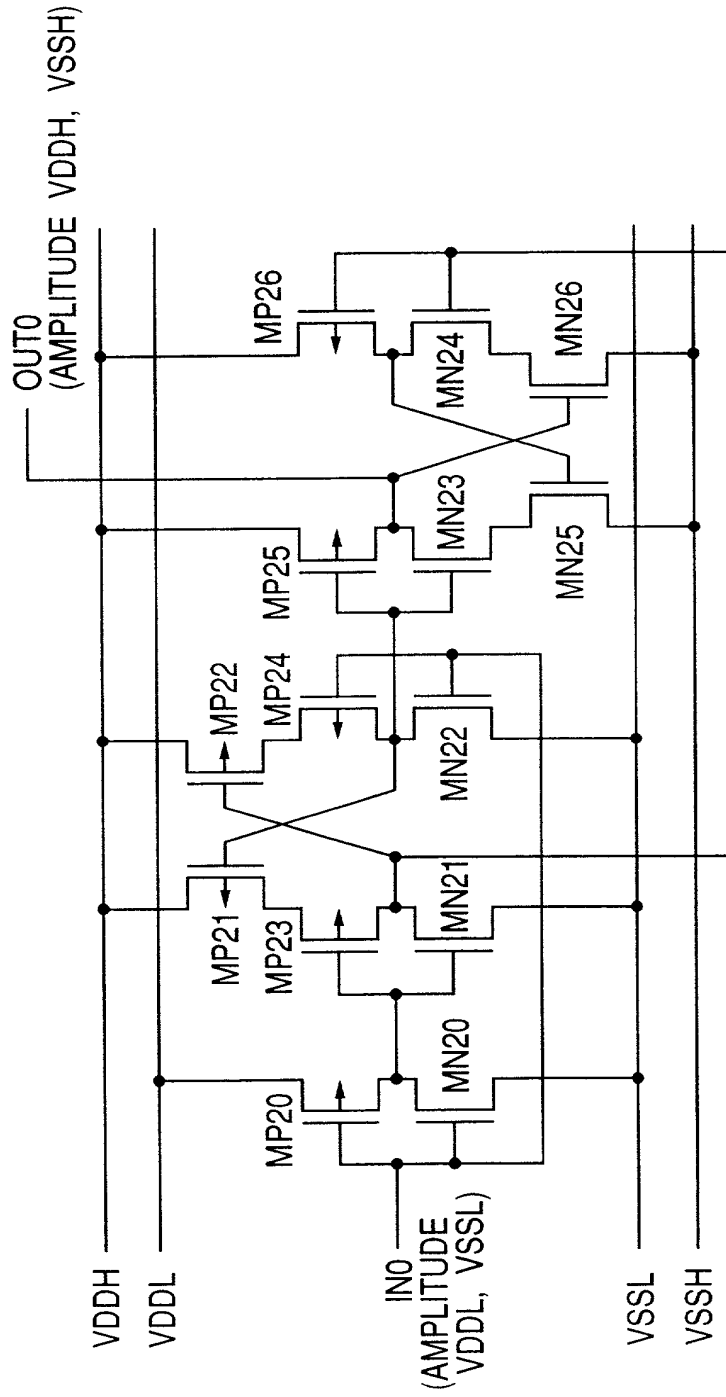


FIG. 17

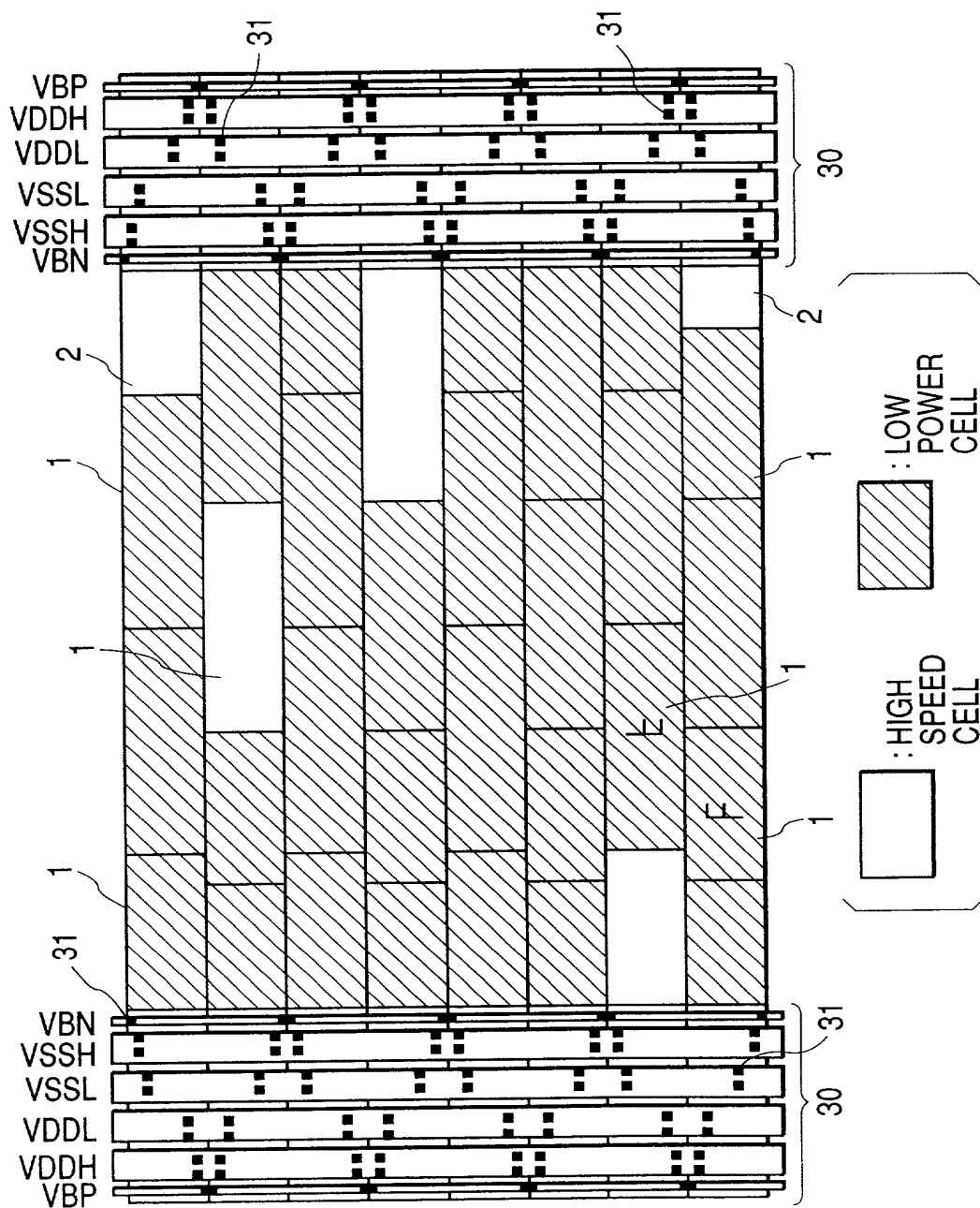
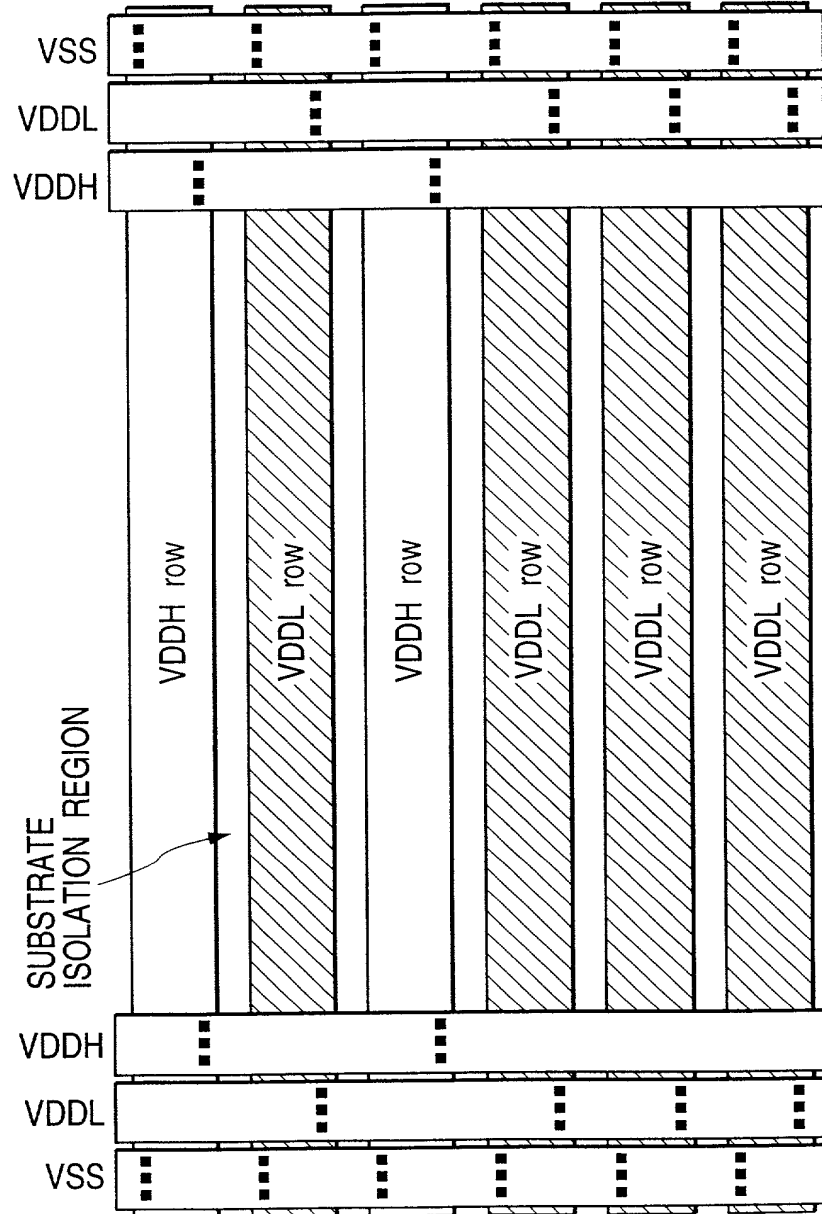
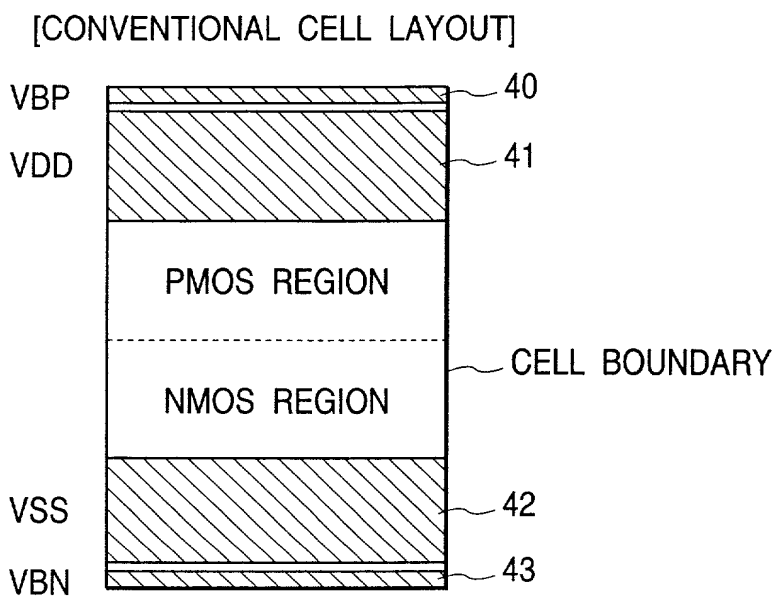


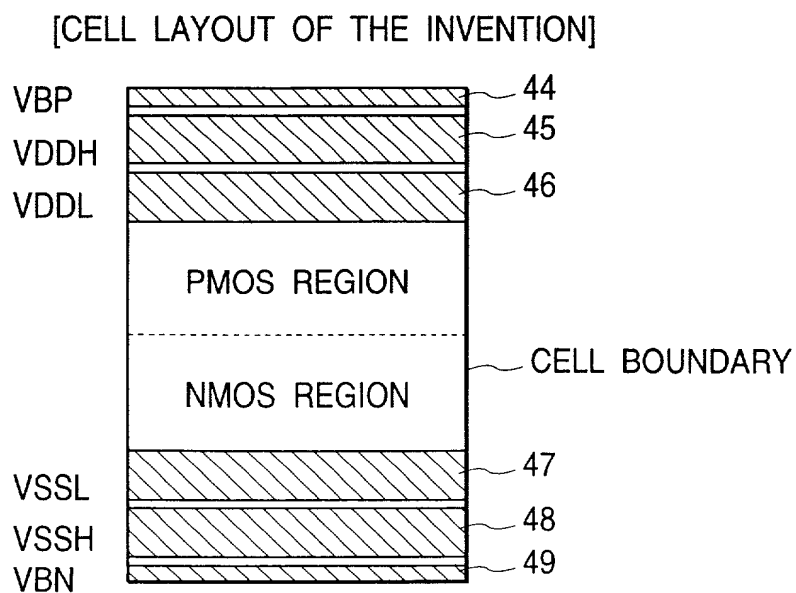
FIG. 18



**FIG. 19(A)**



**FIG. 19(B)**



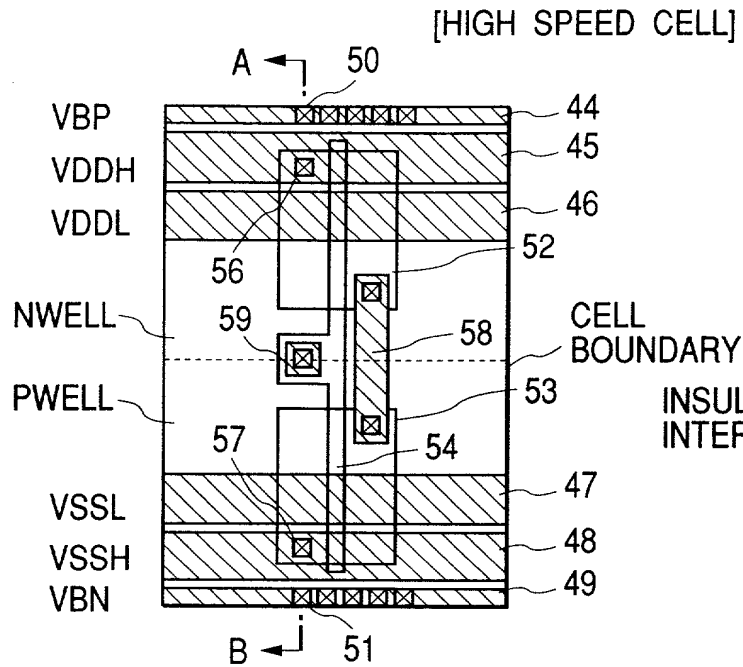
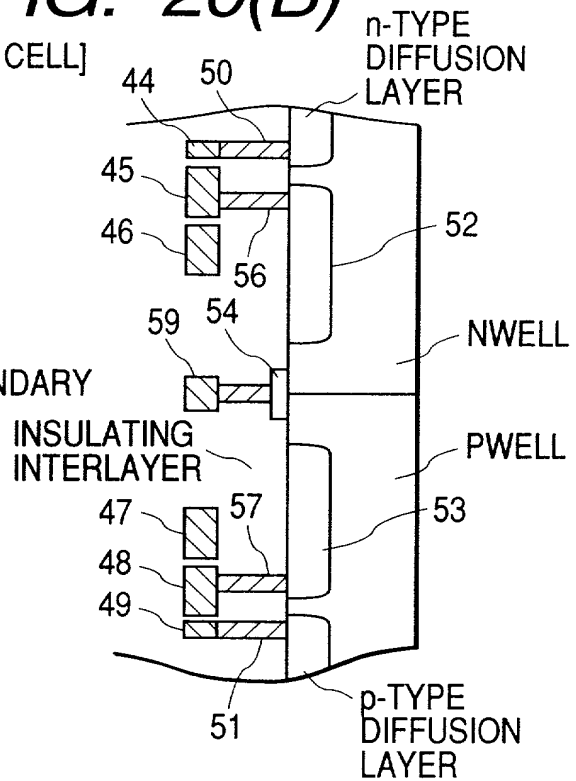
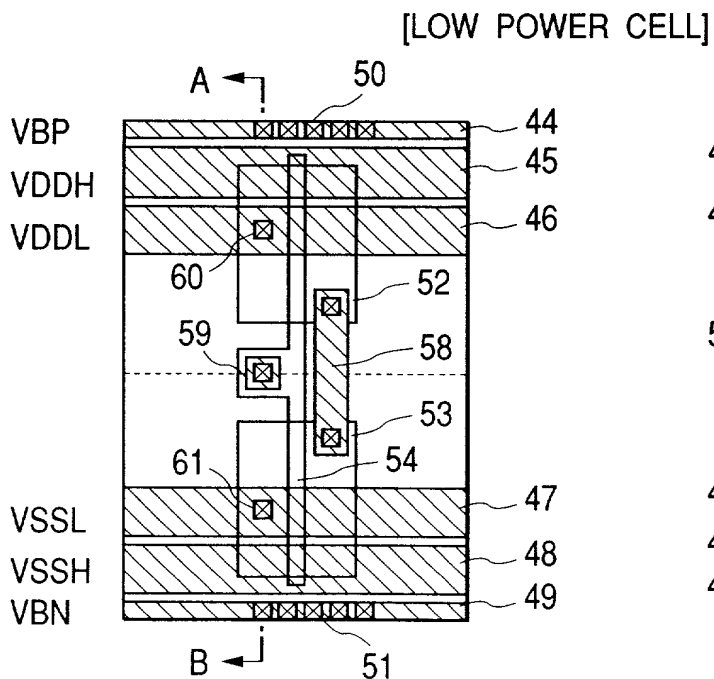
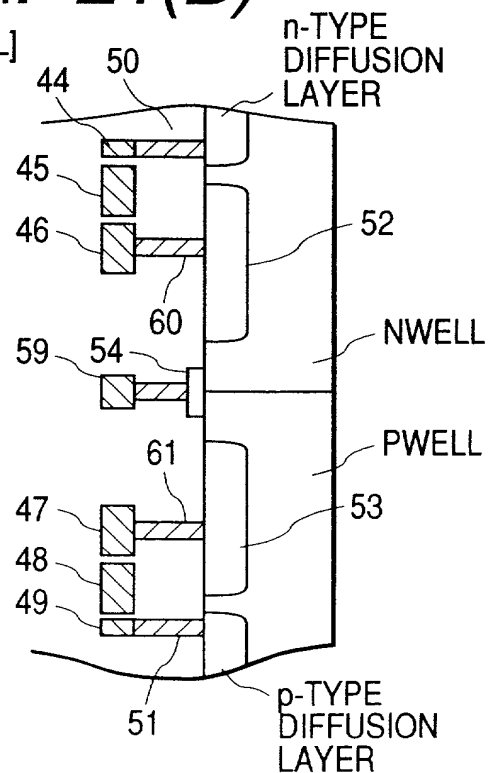
**FIG. 20(A)****FIG. 20(B)****FIG. 21(A)****FIG. 21(B)**



FIG. 22

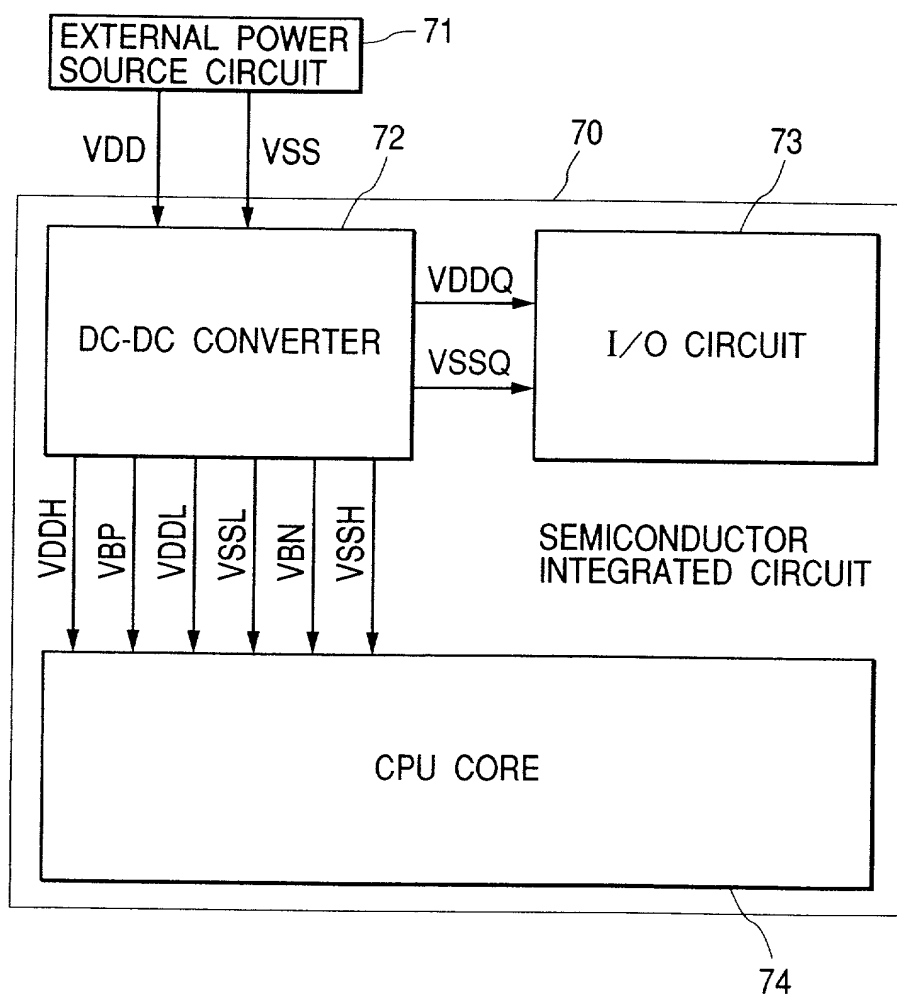


FIG. 23

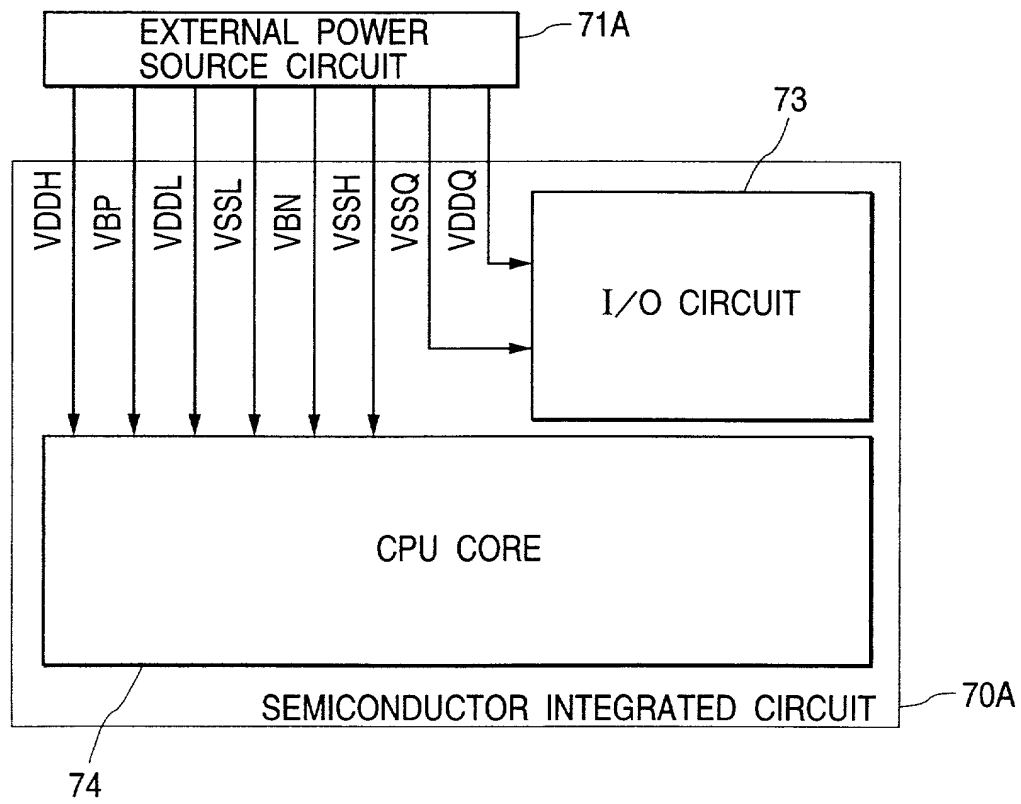
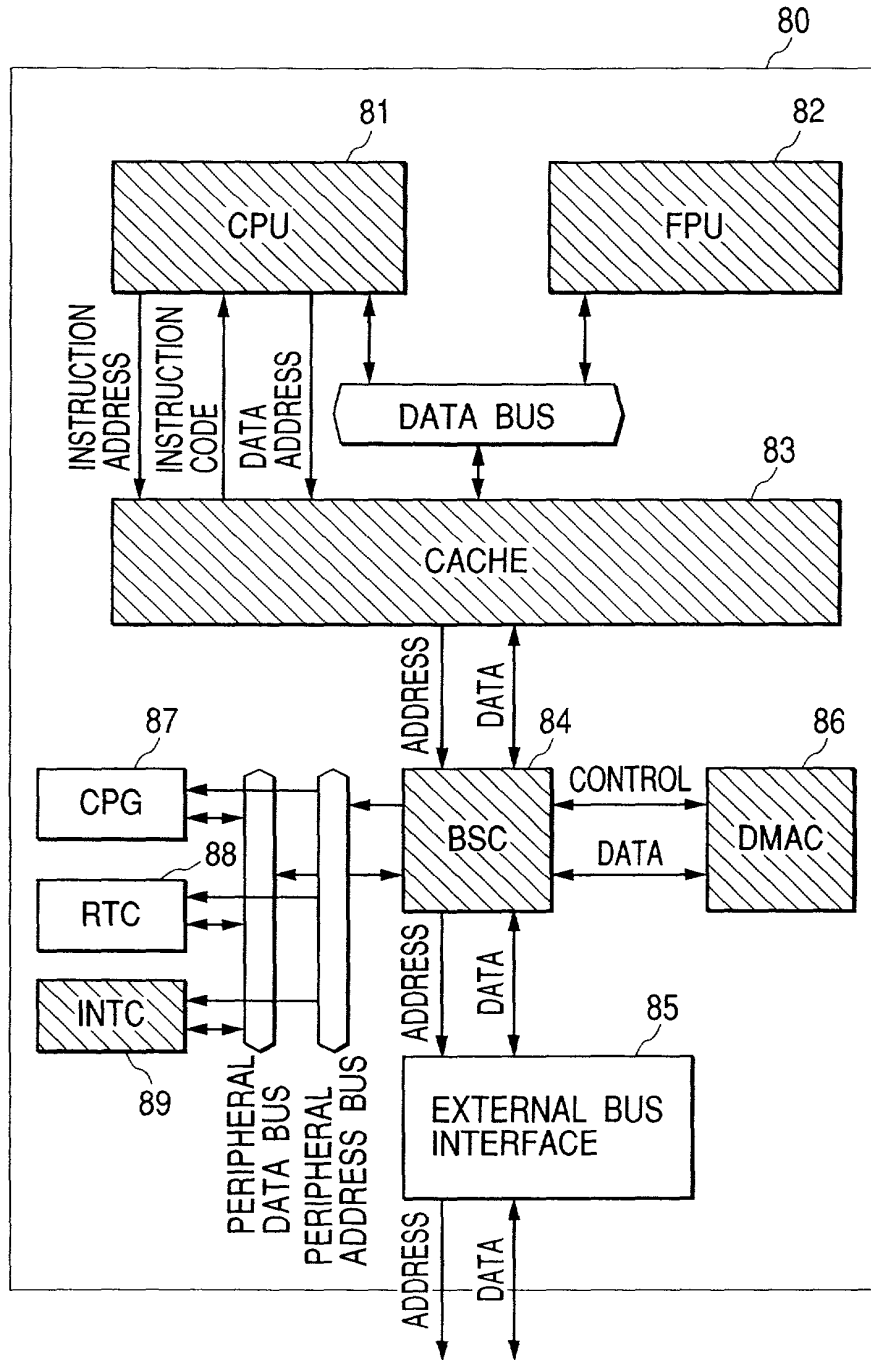
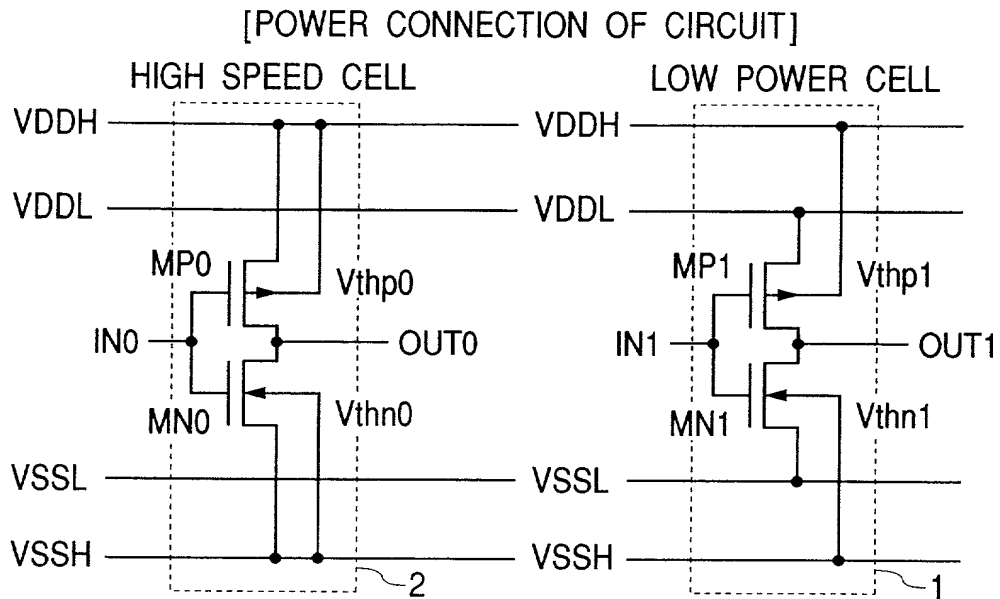
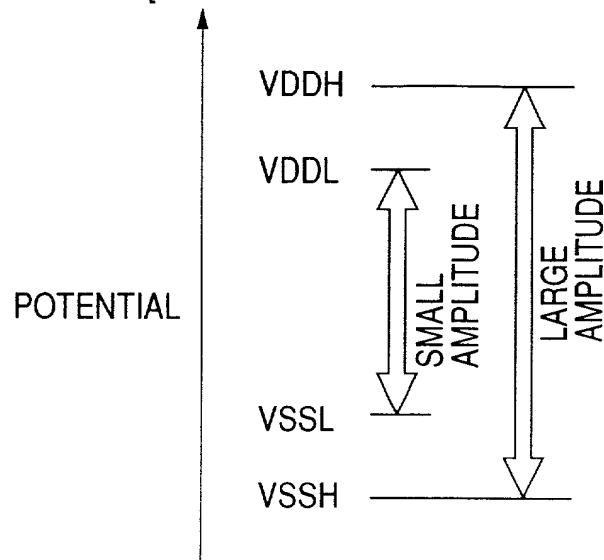


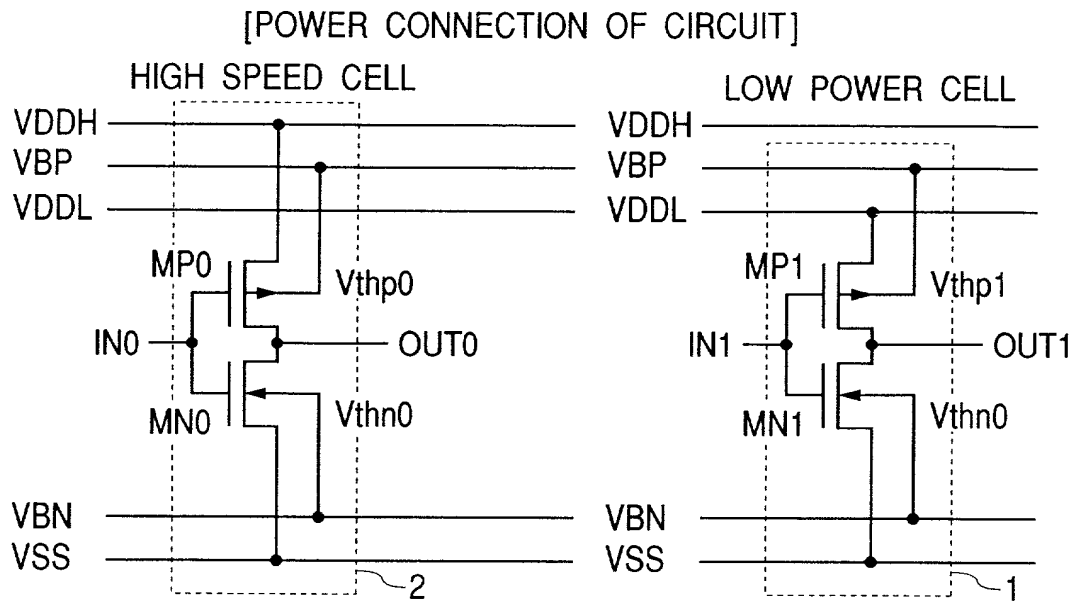
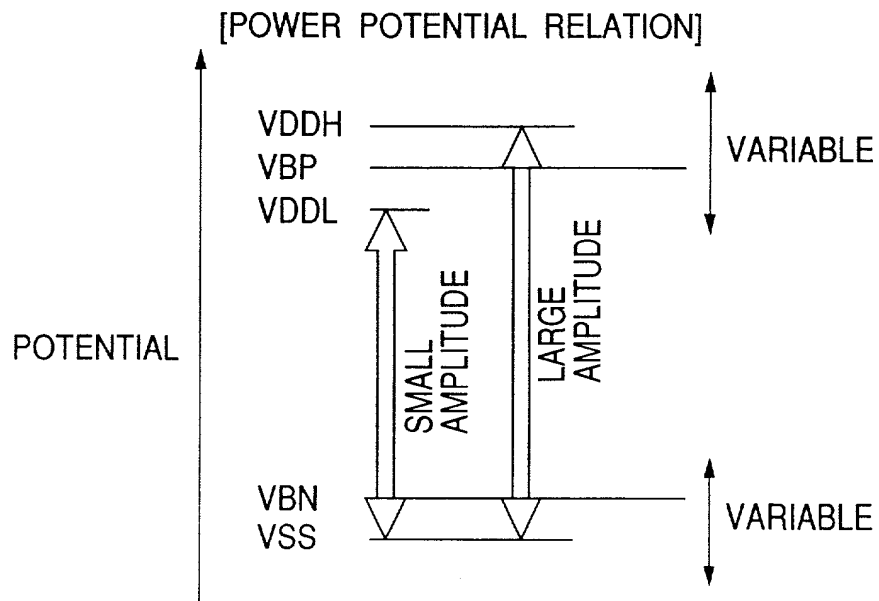
FIG. 24

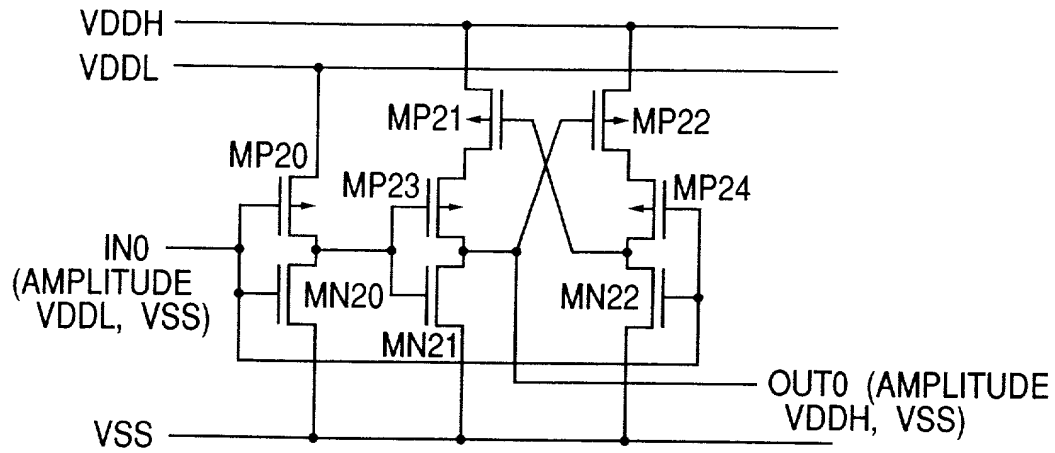


**FIG. 25****FIG. 26**

[POWER POTENTIAL RELATION]



**FIG. 27****FIG. 28**

**FIG. 29****FIG. 30**